TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74HC273AP,TC74HC273AF

Octal D-Type Flip Flop with Clear

The TC74HC273A is a high speed CMOS OCTAL D-TYPE FLIP FLOP fabricated with silicon gate C²MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

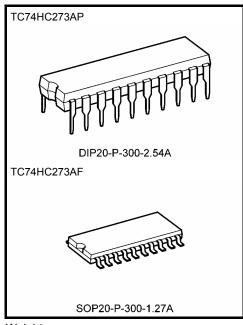
Information signals applied to D inputs are transferred to the Q outputs on the positive going edge of the clock pulse.

When the \overline{CLR} input is held "L", the Q outputs are at a low logic level independent of the other inputs.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

Features

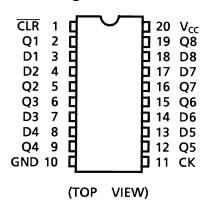
- High speed: $f_{max} = 67 \text{ MHz}$ (typ.) at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 4 \mu A \text{ (max)}$ at $T_{a} = 25 \text{°C}$
- High noise immunity: $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (min)
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance: | I_{OH} | = I_{OL} = 4 mA (min)
- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: V_{CC} (opr) = 2~6 V
- \bullet Pin and function compatible with 74LS273



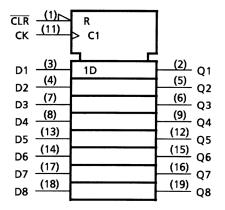
Weight

DIP20-P-300-2.54A : 1.30 g (typ.) SOP20-P-300-1.27A : 0.22 g (typ.)

Pin Assignment



IEC Logic Symbol

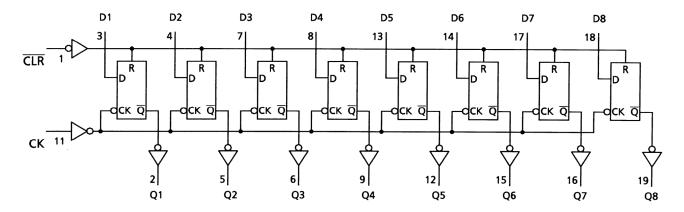


Truth Table

	Inputs		Output	Function			
CLR	D	CK	Q	Tunction			
L	Х	Х	L	Clear			
Н	L		L	_			
Н	Н		Н	_			
Н	Х	\neg	Qn	No change			

X: Don't care

System Diagram



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Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~7	V
DC input voltage	V _{IN}	-0.5~V _{CC} + 0.5	V
DC output voltage	V _{OUT}	-0.5~V _{CC} + 0.5	V
Input diode current	I _{IK}	±20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V _{CC} /ground current	Icc	±50	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T _{stg}	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of $Ta = -40\sim65$ °C. From Ta = 65 to 85°C a derating factor of -10 mW/°C shall be applied until 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V _{CC}	2~6	V
Input voltage	V _{IN}	0~V _{CC}	V
Output voltage	V _{OUT}	0~V _{CC}	٧
Operating temperature	T _{opr}	-40~85	°C
		0~1000 (V _{CC} = 2.0 V)	
Input rise and fall time	t _r , t _f	0~500 (V _{CC} = 4.5 V)	ns
		0~400 (V _{CC} = 6.0 V)	

Note: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

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Electrical Characteristics

DC Characteristics

		Test Condition			-	Га = 25°C)	Ta = -40~85°C		Unit
Characteristics	Characteristics Symbol				Min	Тур.	Max	Min	Max	
				2.0	1.50	_	_	1.50	_	
High-level input voltage	V _{IH}		_	4.5	3.15	_	_	3.15	_	V
1 11 9 1				6.0	4.20	_	_	4.20	_	
				2.0	_	_	0.50	_	0.50	
Low-level input voltage	V _{IL}		_	4.5	_	_	1.35	_	1.35	V
				6.0	_	_	1.80	_	1.80	
	V _{ОН}	VIN = VIH or VIL		2.0	1.9	2.0	_	1.9	_	
			I _{OH} = -20 μA	4.5	4.4	4.5	_	4.4	_	
High-level output voltage				6.0	5.9	6.0	_	5.9	_	V
ŭ			I _{OH} = -4 mA	4.5	4.18	4.31	_	4.13	_	
			I _{OH} = -5.2 mA	6.0	5.68	5.80	_	5.63	_	
		V _{IN} = V _{IH} or		2.0	_	0.0	0.1	_	0.1	
	V _{OL}		$I_{OL} = 20 \mu A$	4.5	_	0.0	0.1	_	0.1	
Low-level output voltage				6.0	_	0.0	0.1	_	0.1	V
		V _{IL}	I _{OL} = 4 mA	4.5	_	0.17	0.26	_	0.33	
			I _{OL} = 5.2 mA	6.0	_	0.18	0.26	_	0.33	
Input leakage current	I _{IN}	V _{IN} = V _{CC} or GND		6.0	_	_	±0.1	_	±1.0	μА
Quiescent supply current	Icc	$V_{IN} = V_C$	_C or GND	6.0	_	_	4.0	_	40.0	μА

Timing Requirements (input: $t_r = t_f = 6 \text{ ns}$)

Characteristics	Symbol	Test Condition	Test Condition			Ta = -40 ~85°C	Unit
			V _{CC} (V)	Тур.	Limit	Limit	
Minimum nulae width	*		2.0	_	75	95	
Minimum pulse width (CK)	t _{W (L)}	_	4.5	_	15	19	ns
(CK)	t _{W (H)}		6.0	_	13	16	
Minimum pulse width			2.0	_	75	95	
(CLR)	t _{W (L)}	_	4.5	_	15	19	ns
(OLK)			6.0		13	16	
			2.0	_	75	95	
Minimum set-up time	t _s	_	4.5	_	15	19	ns
			6.0		13	16	
			2.0	_	0	0	
Minimum hold time	t _h	_	4.5	_	0	0	ns
			6.0	_	0	0	
Minimum removal time			2.0	_	50	65	
(CLR)	t _{rem}	_	4.5	_	10	13	ns
(CLR)			6.0	_	9	11	
			2.0	_	6	5	
Clock frequency	f	_	4.5	_	30	24	MHz
			6.0	_	35	28	



AC Characteristics ($C_L = 15 \text{ pF}$, $V_{CC} = 5 \text{ V}$, $Ta = 25^{\circ}\text{C}$, input: $t_r = t_f = 6 \text{ ns}$)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Output transition time	t _{TLH} t _{THL}	_	_	4	8	ns
Propagation delay time (CK-Q)	t _{pLH}	_	_	15	25	ns
Propagation delay time (CLR -Q)	t _{pLH}	_	_	16	27	ns
Maximum clock frequency	f _{max}		40	67	_	MHz

AC Characteristics ($C_L = 50 \text{ pF}$, input: $t_r = t_f = 6 \text{ ns}$)

		Test Condition		-	Ta = 25°C			Ta = -40~85°C	
Characteristics	Symbol			Min	Тур.	Max	Min	Max	Unit
	t		2.0	_	25	75	_	95	
Output transition time	t _{TLH}	_	4.5	_	7	15	_	19	ns
	t _{THL}		6.0	_	6	13	_	16	
Propagation delay	4		2.0	_	54	145	_	180	
time	t _{pLH}	_	4.5	_	18	29	_	36	ns
(CK-Q)	t_{pHL}		6.0	_	15	25	_	31	
Propagation delay	4		2.0	_	60	160	_	200	
time	t _{pLH}	_	4.5	_	20	32	_	40	ns
(CLR -Q)	t_{pHL}		6.0	_	17	27	_	34	
			2.0	6	18	_	5	_	
Maximum clock frequency	f _{max}	_	4.5	30	56	_	24	_	MHz
in equality			6.0	35	66	_	28	_	
Input capacitance	C _{IN}	_		_	5	10	_	10	pF
Power dissipation capacitance	C _{PD} (Note)	_		_	43	_	_	_	pF

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 I_{CC} (opr) = $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8$ (per flip flop)

And the total $C_{\mbox{\scriptsize PD}}$ when n pcs. of flip flop operate can be gained by the following equation:

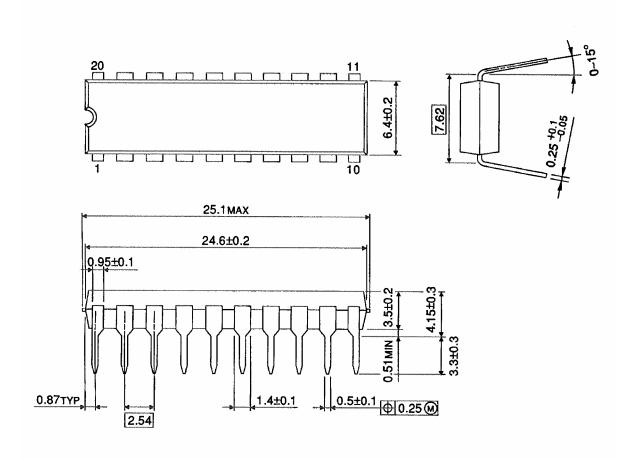
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 C_{PD} (total) = 32 + 11·n

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Package Dimensions

DIP20-P-300-2.54A Unit: mm

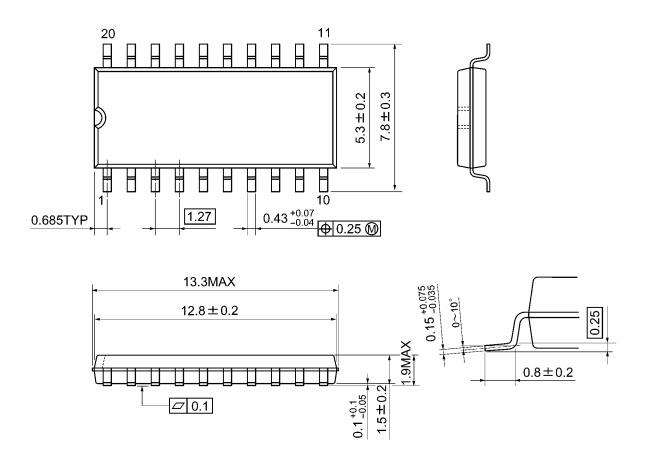


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Weight: 1.30 g (typ.)

Package Dimensions

SOP20-P-300-1.27A Unit: mm



Weight: 0.22 g (typ.)

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20070701-EN GENERAL

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